



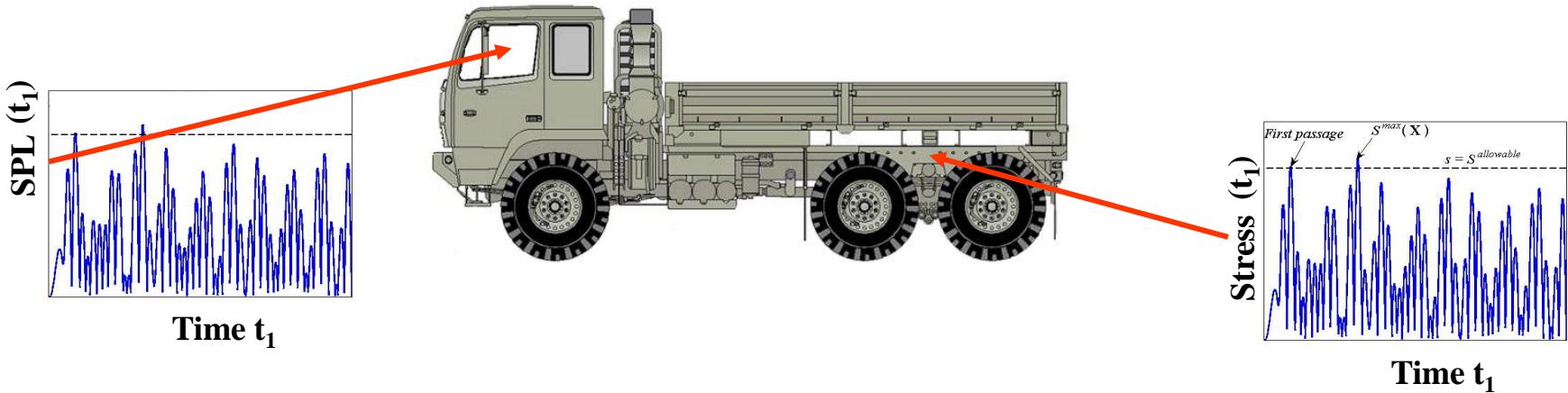
# **Design for Lifecycle Cost using Time-Dependent Reliability Analysis**

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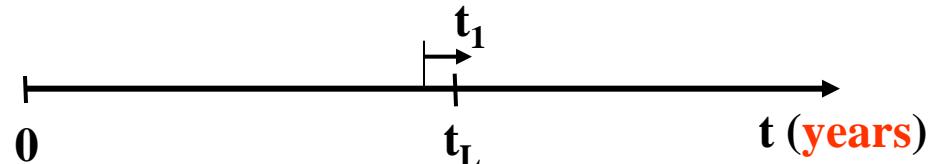
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# Problem Definition



$$\text{Response}(t) = f [ E(t), \text{Degradation/Wear}(t), \text{Load}(t_1) ]$$



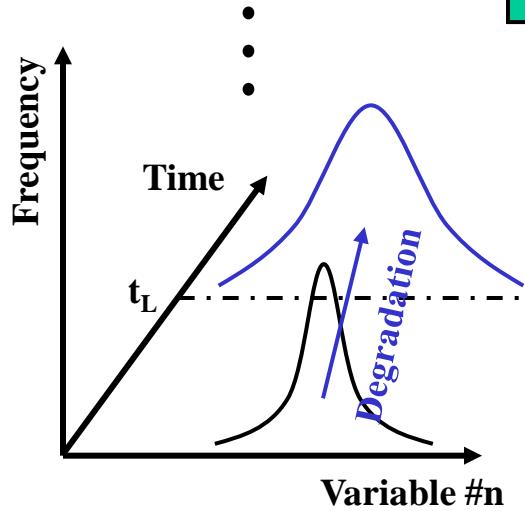
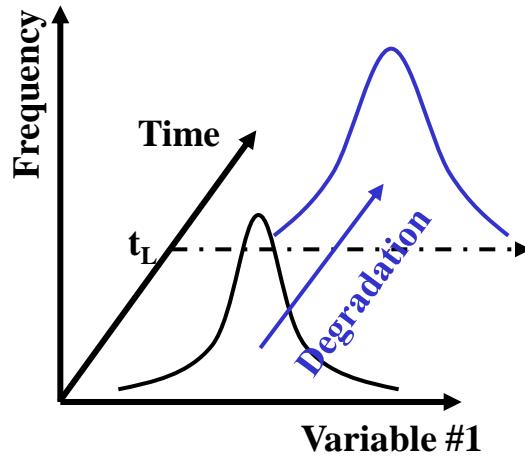
$$E(t) = E_0(1 - D * t)$$

Random Process Degradation Rate  
(Random Variable) →  $E(t_L)$  is a R. V.

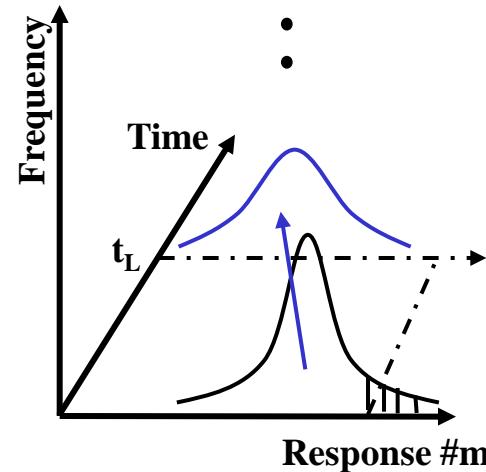
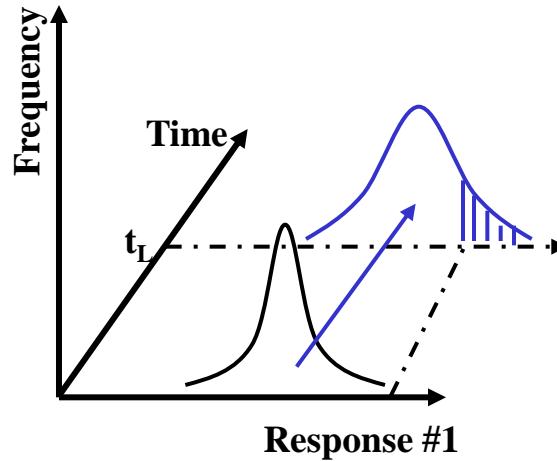
Two time scales;  $t$  and  $t_1$

# Problem Definition

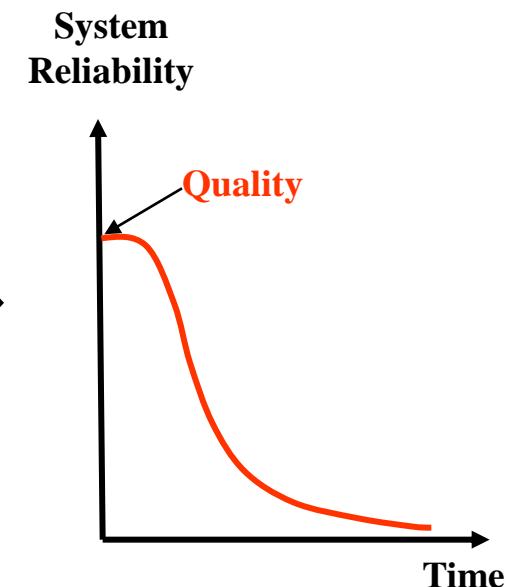
## Input variables



## System Responses



## System Reliability



**Quality = Reliability ( $t = 0$ )**

# Definitions / Observations

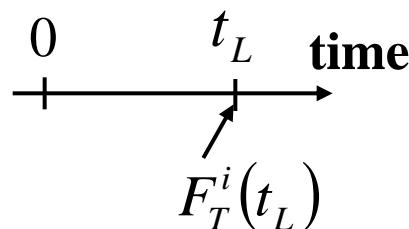
**Reliability:** Ability of a system to carry out a function in a time period  $[0, t_L]$

$$p_f^c = P(t \leq t_L) = F_T^c(t_L) \quad \text{Prob. of Time to Failure}$$

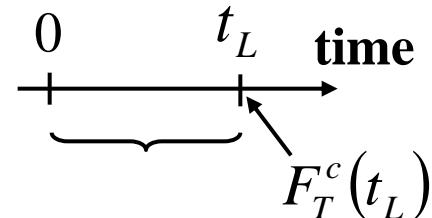
$$F_T^c(t_L) = P(\exists t \in [0, t_L], \text{such that } g(\mathbf{X}(t), t) \leq 0) \quad \text{Cumulative Prob. of Failure}$$

$$F_T^i(t_L) = P(g(\mathbf{X}(t_L), t_L) \leq 0) \quad \text{Instantaneous Prob. of Failure}$$

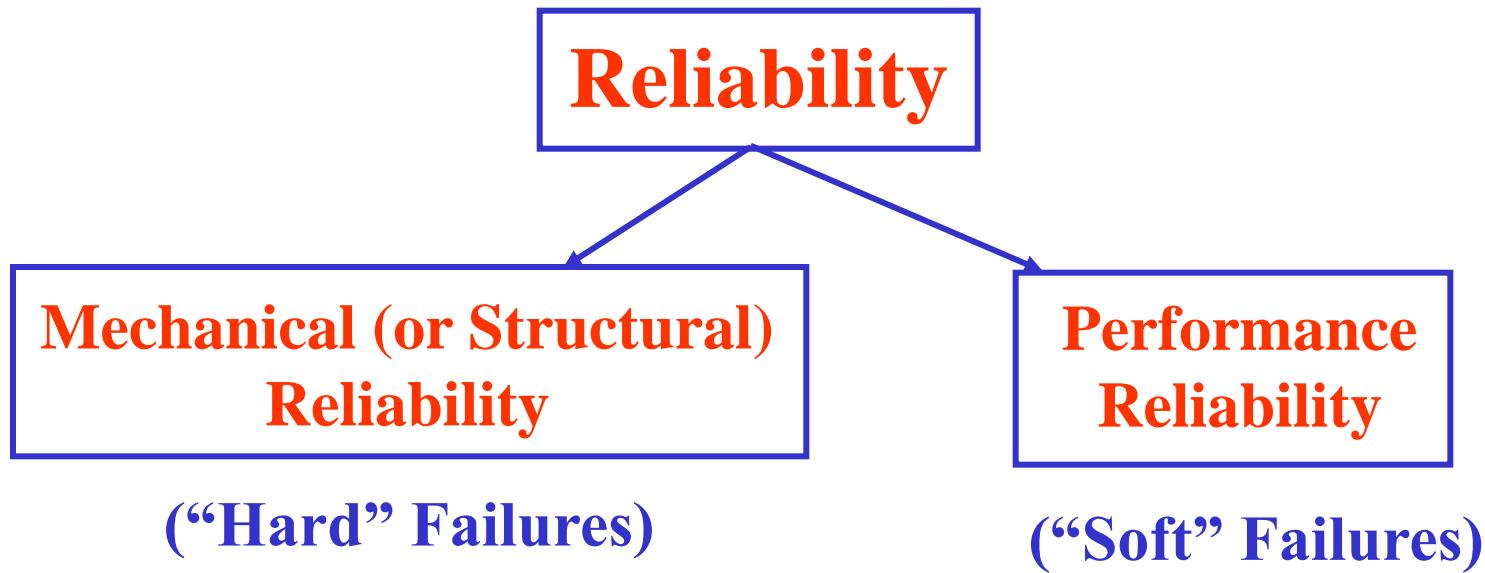
## Time-Invariant Reliability



## Time-Variant Reliability



# Definitions / Observations



**Quality:** Performance Reliability at  $t = 0$

**OR**

Conformance to Specifications at  $t = 0$

**Performance Reliability = Quality over Time**

# Design for Lifecycle Cost

$$C_L(\mathbf{d}, \mathbf{X}, t_f, r) = C_P(\mathbf{d}, \mathbf{X}) + C_I(\mathbf{d}, \mathbf{X}, t_0) + C_V^E(\mathbf{d}, \mathbf{X}, t_f, r)$$

Lifecycle Cost      Production Cost      Inspection Cost      Expected Variable Cost

$$C_V^E(\mathbf{d}, \mathbf{X}, t_f, r) = \int_0^{t_f} c_F(t) e^{-rt} f_T^c(t) dt$$

Final time      Interest rate  
 Cost of failure at time t      PDF of time to failure

$$F_T^c(t_L) = P(\exists t \in [0, t_L], \text{such that } g(\mathbf{X}(t), t) \leq 0)$$

# Design for Lifecycle Cost

$$\min_{\mathbf{d}, \boldsymbol{\mu}_{\mathbf{X}}, \boldsymbol{\sigma}_{\mathbf{X}}} C_L(\mathbf{d}, \mathbf{X}, t_f, r)$$

# of time-dependent  
limit states

s. t.  $F_{T_i}^c(\mathbf{d}, \mathbf{X}, t) \leq p_{f_i}^t$  for  $i = 1, 2, \dots, n$

$$\mathbf{d}_L \leq \mathbf{d} \leq \mathbf{d}_U$$

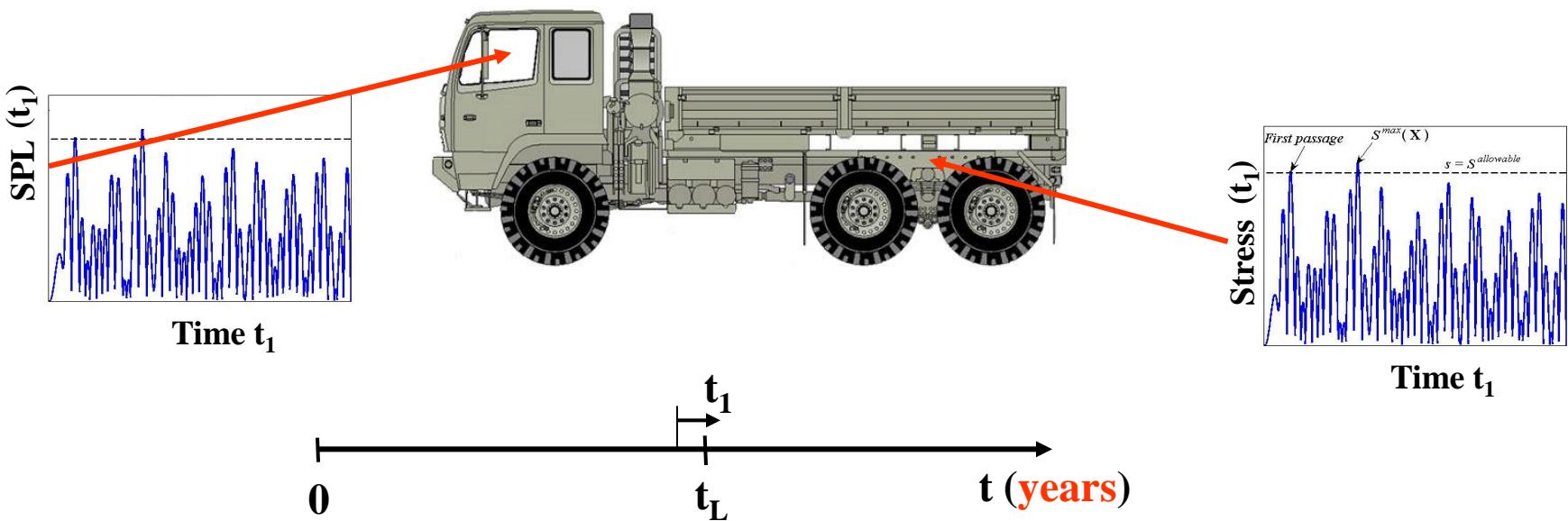
e.g.  $p_f^t = 0.05$  after  $t = 5$  years

$$\boldsymbol{\mu}_{\mathbf{X}_L} \leq \boldsymbol{\mu}_{\mathbf{X}} \leq \boldsymbol{\mu}_{\mathbf{X}_U}$$

$$\boldsymbol{\sigma}_{\mathbf{X}_L} \leq \boldsymbol{\sigma}_{\mathbf{X}} \leq \boldsymbol{\sigma}_{\mathbf{X}_U}$$

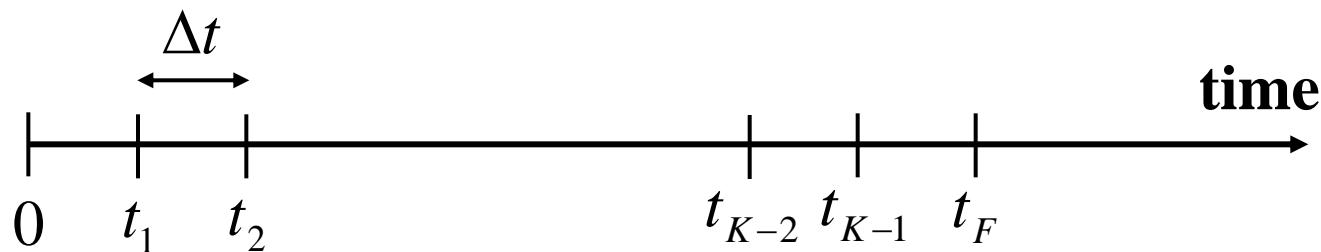
# Calculation of Cumulative Probability of Failure

- Series system approach for  $[0, t_f]$
- Reliability estimation at time  $t_L$  ( $0 < t_L < t_f$ );  
**multiple MPP case**



# Calculation of Cumulative Probability of Failure

$$F_T^c(t_F) = P(\exists t \in [0, t_F], \text{such that } g(\mathbf{X}(t), t) \leq 0)$$



$$t_F = K\Delta t$$

$$F_T^c(t_F) = P\left(\bigcup_{k=0}^K g(\mathbf{X}(t_k), t_k) \leq 0\right)$$

**Series System  
Prob. of Failure**

# Cumulative Probability of Failure (PHI2 Method)

$$F_T^c(t_F) \approx F_T^i(0) + E[N^+(0, t_F)]$$

$$E[N^+(0, t_F)] = \int_0^{t_F} \nu^+(t) dt$$

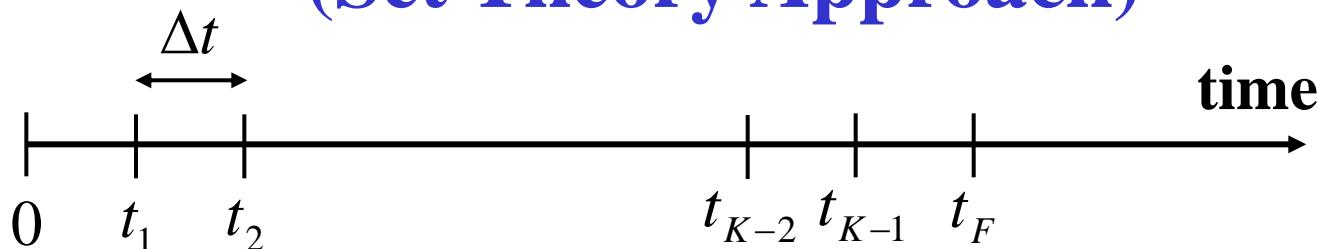
**up-crossing rate**

**# of up-crossings in  $[0, t_F]$**

$$\nu^+(t) = \lim_{\Delta t \rightarrow 0} \frac{P[(g(\mathbf{X}(t), t) > 0) \cap (g(\mathbf{X}(t + \Delta t), t + \Delta t) \leq 0)]}{\Delta t}$$

$$\nu_{PHI2}^+(t) = \frac{\Phi_2[\beta(t), -\beta(t + \Delta t), \rho_{gg}(t, t + \Delta t)]}{\Delta t}$$

# Cumulative Probability of Failure (Set Theory Approach)



$$t_F = K\Delta t$$

$$F_T^c(t_F) = P\left(\bigcup_{k=0}^K g(\mathbf{X}(t_k), t_k) \right)$$

**Define:**  $IF_k = \{g(\mathbf{X}(t_k), t_k) \leq 0\}$  **(Instantaneous Failure Event)**

**then:**  $\mathbf{CF}_K = \bigcup_{k=0}^K IF_k$  **(Cumulative Failure)**

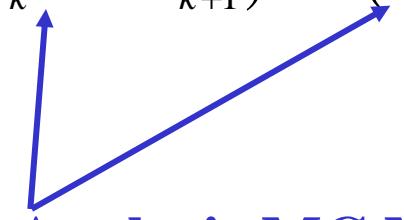
$\Delta F_k = \overline{\mathbf{CF}_k} \cap \mathbf{CF}_{k+1}$  **(Incremental Failure)**

$$P(\Delta F_k) \approx P(\mathbf{CF}_k \cup \mathbf{CF}_{k+1}) - P(\mathbf{CF}_k)$$

# Cumulative Probability of Failure (Set Theory Approach)

$$F_T^c(t_F) = P\left(\bigcup_{k=0}^K g(\mathbf{X}(t_k), t_k)\right) \approx P(IF_0) + \sum_{k=0}^{K-1} P(\Delta \mathbf{F}_k)$$

$$P(\Delta \mathbf{F}_k) \approx P(\mathbf{CF}_k \cup \mathbf{CF}_{k+1}) - P(\mathbf{CF}_k)$$



**Probabilistic Re-Analysis MC Method**

# Cumulative Probability of Failure (PHI2 Method)

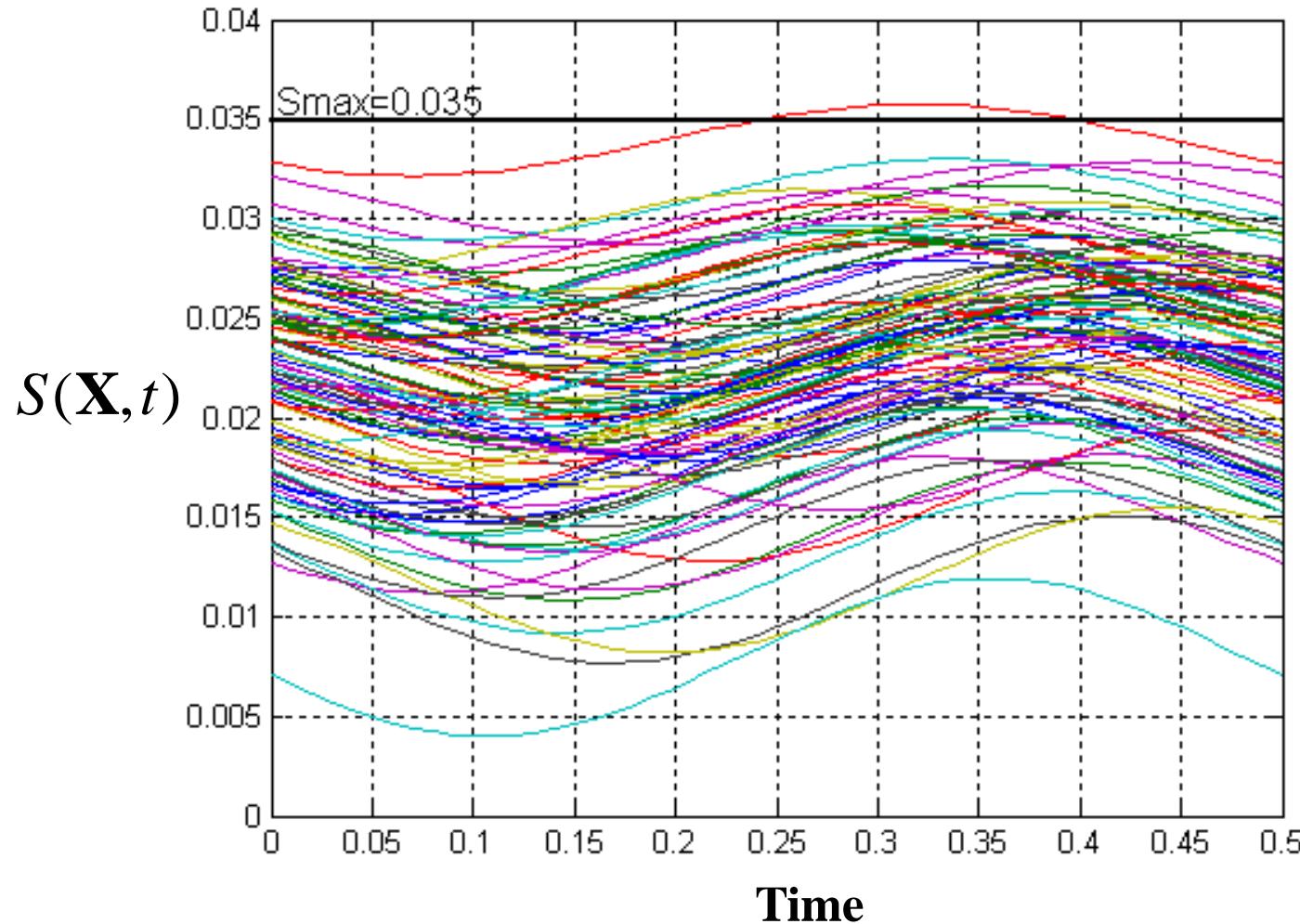
$$S(\mathbf{X}, t) = \frac{1}{18} - [12,000 - 1,000 \sin(4\pi t + X_3)] * \frac{10^4}{X_1 X_2}$$

$$X_1 \sim N(2.29 * 10^{-3}, 0.229 * 10^{-3})$$

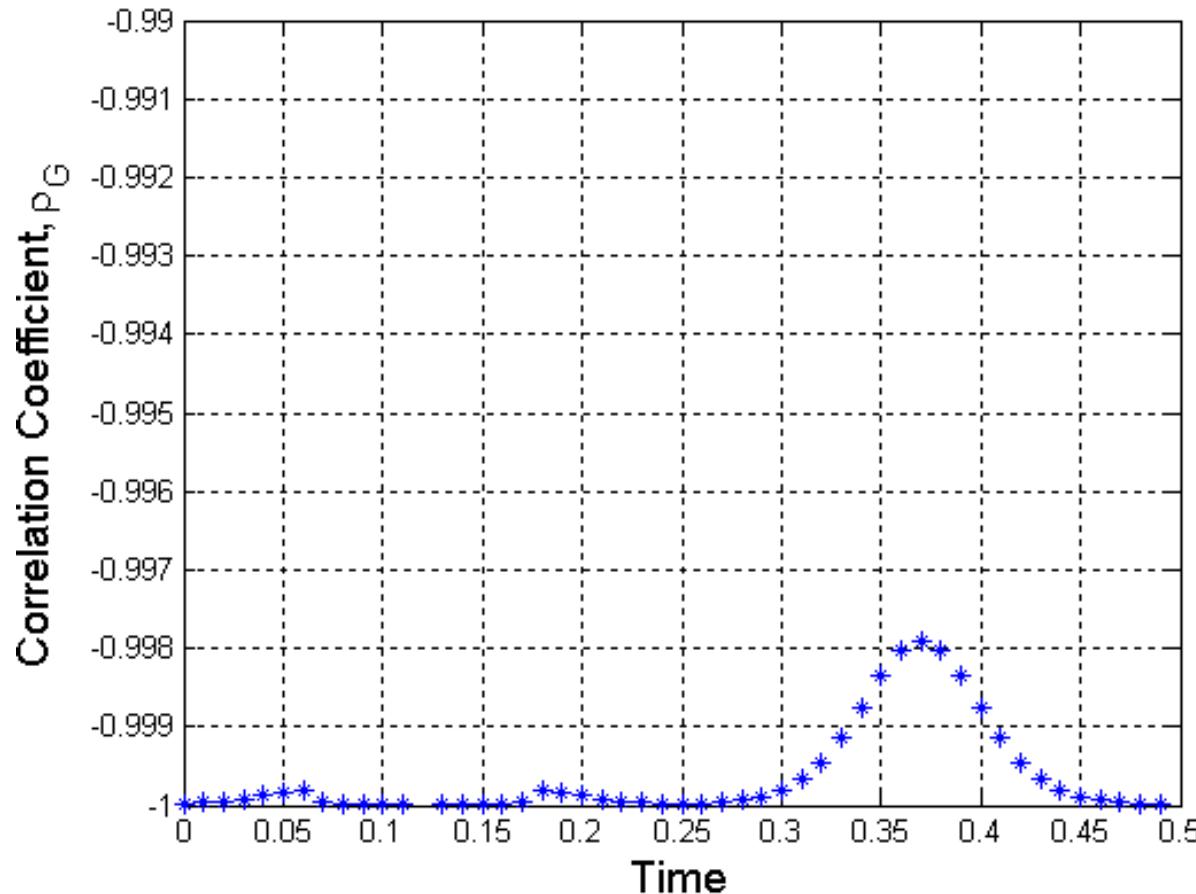
$$X_2 \sim N(2 * 10^{11}, 0.2 * 10^{11})$$

$$X_3 \sim N(0, 0.7)$$

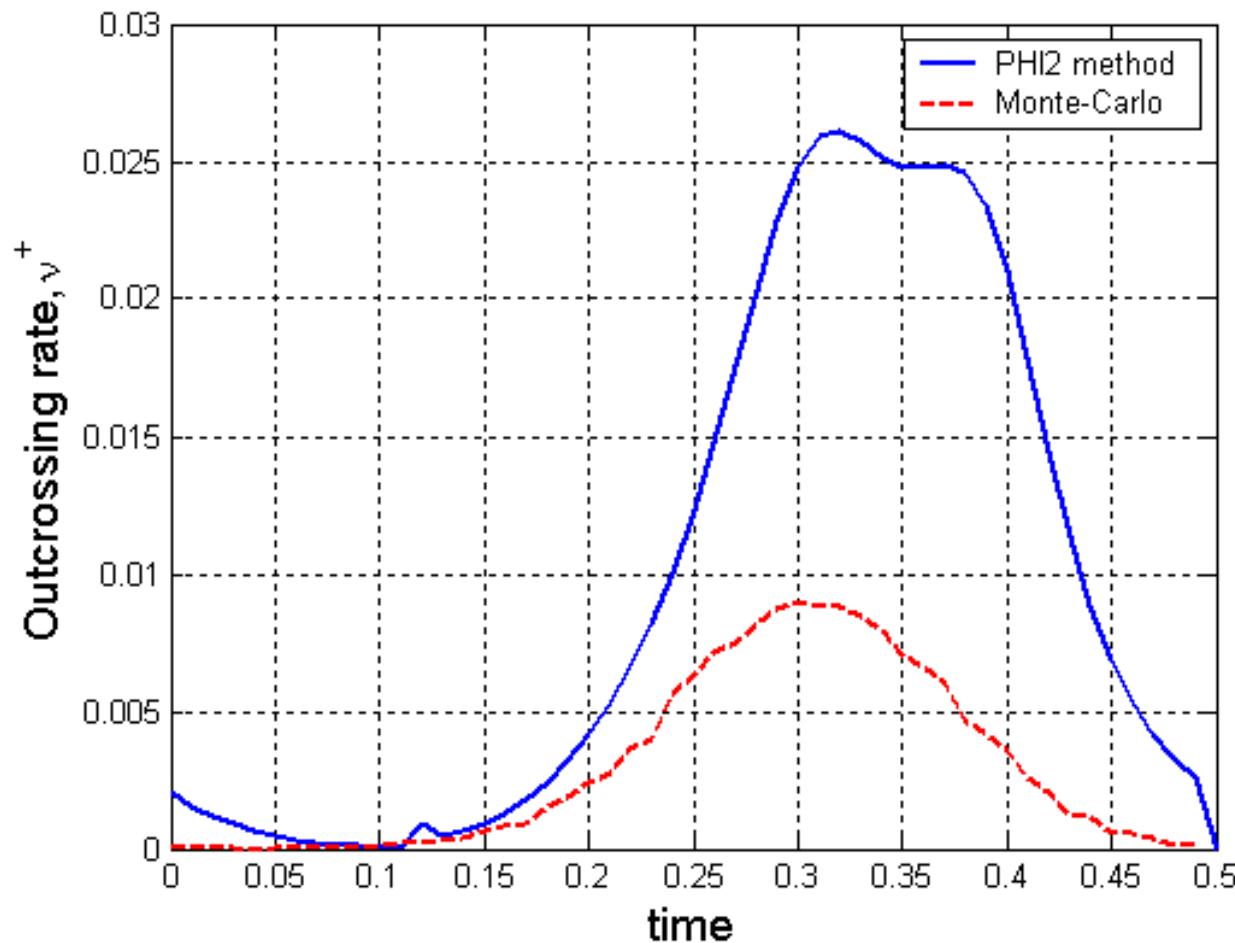
# Cumulative Probability of Failure (PHI2 Method)



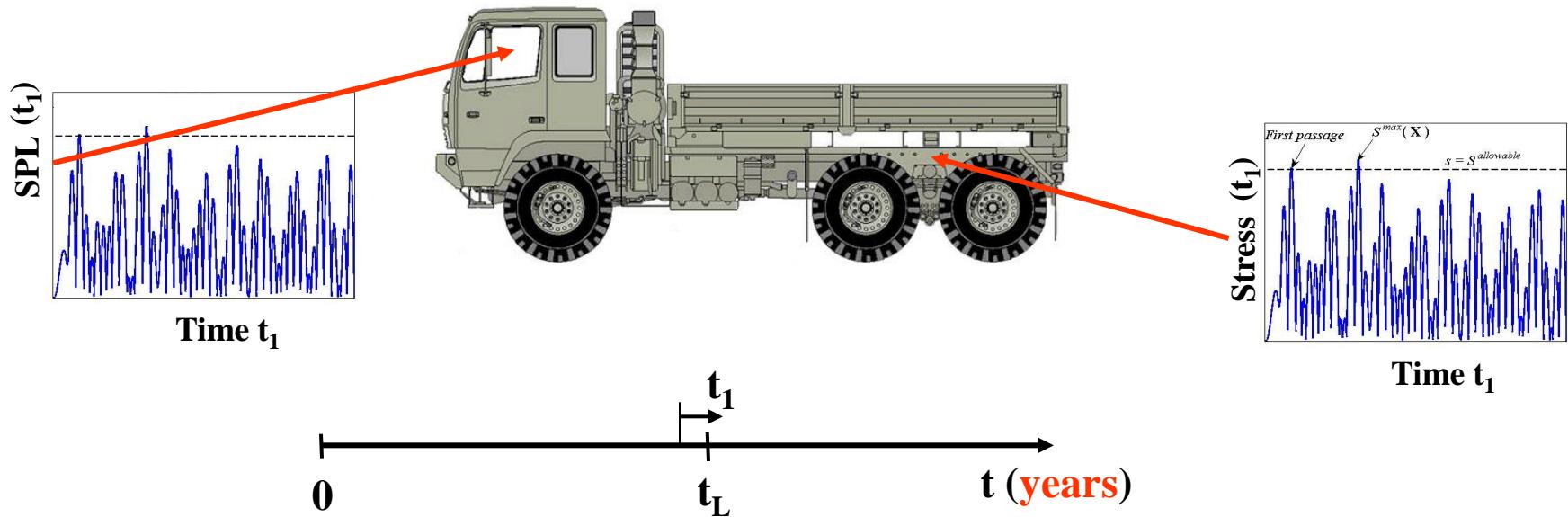
# Cumulative Probability of Failure (PHI2 Method)



# Cumulative Probability of Failure (PHI2 Method)



# Reliability Estimation at Time $t_L$

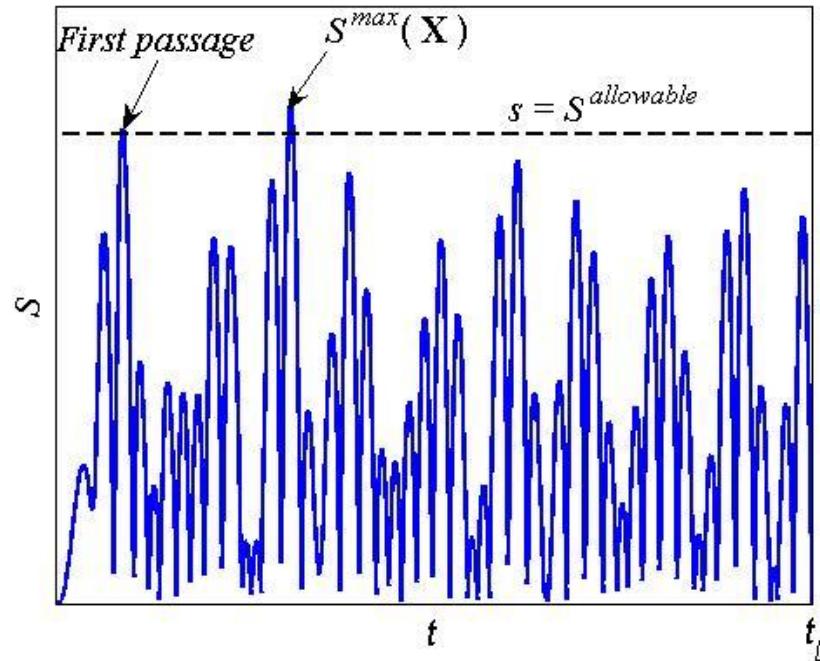


- Time-dependent reliability
- Multiple MPPs
- Niching genetic algorithm

# Main Points

- **Time-dependent reliability problem is transformed into a time independent reliability problem for solving a level-crossing problem**
- **Multiple disjoint failure domains may exist**

# Time-dependent Reliability Analysis of a Random Process



- Transfer a time-dependent process to a time independent response:

$$S = S(\mathbf{X}, t), \quad t_{\min} \leq t \leq t_{\max} \quad \Rightarrow \quad S^{\max}(\mathbf{X}) = \max_{t_{\min} \leq t \leq t_{\max}} S(\mathbf{X}, t)$$

- Time-independent limit state:

$$g(\mathbf{X}) = S^{\text{allowable}} - S^{\max}(\mathbf{X}) = 0$$

# Time-dependent Reliability Analysis of a Random Process

## ➤ Double loop approach:

**Outerloop:** Find MPP's

$$\beta_j = \min_{\mathbf{U} \in R^n} \|\mathbf{U}\|_2$$

$$\text{s.t. } g(\mathbf{X}) = S^{\text{allowable}}(\mathbf{X}) - S^{\max}(\mathbf{X}) = 0$$

$$\mathbf{X} = \boldsymbol{\mu}_{\mathbf{X}} + \boldsymbol{\sigma}_{\mathbf{X}} \mathbf{U}$$

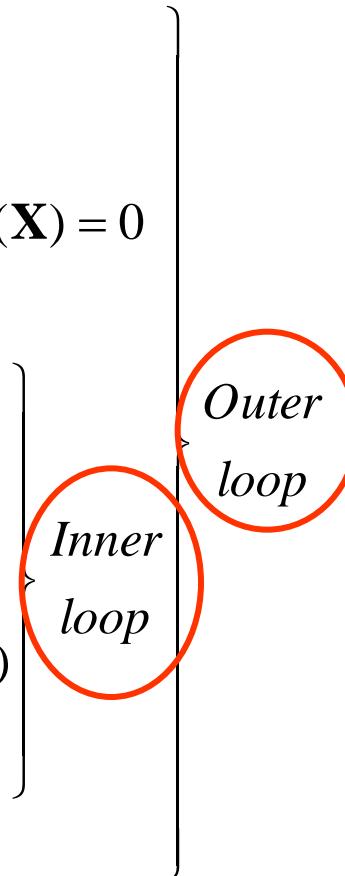
**Inner loop:**

Find maximum response  
in time domain

$$S_j^{\max}(\mathbf{X}) = \max_{t_{\min} \leq t \leq t_{\max}} S_j(\mathbf{X}, t)$$

**End of innerloop**

**End of outerloop**



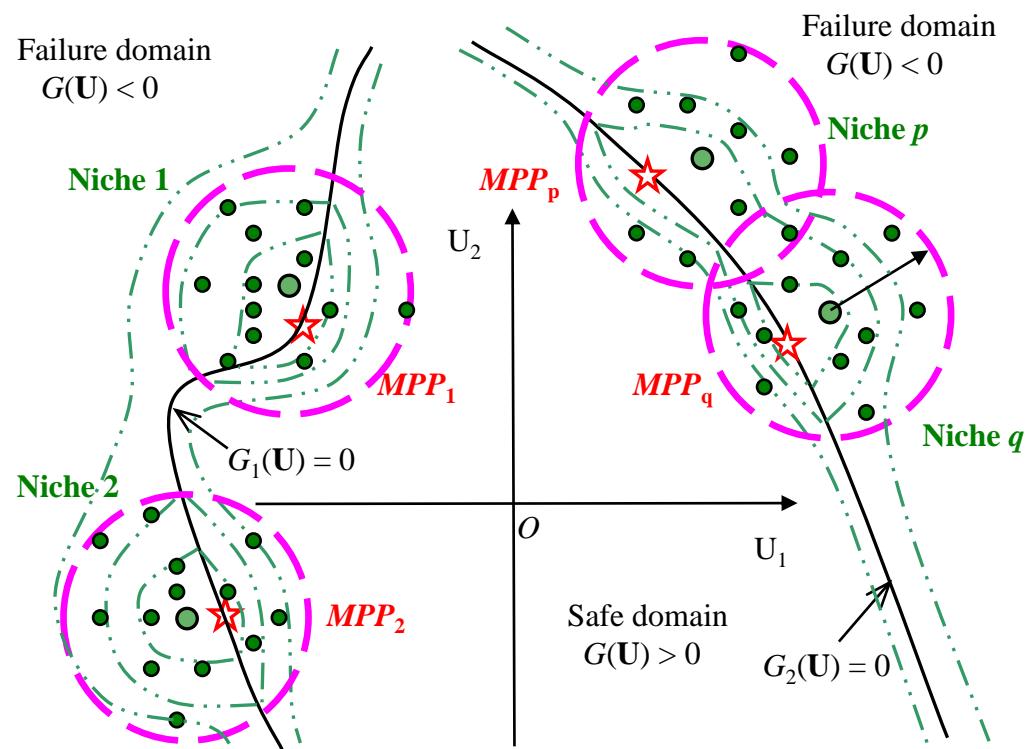
# Time-dependent Reliability Analysis of a Random Process

## ➤ Definitions

- ✓ Actual MPPs
- ✓ Niches

## ➤ Observations

- ✓ Niche center is an approximate MPP
- ✓ Niching GA finds ALL approximate MPPs



# Time-dependent Reliability Analysis of a Random Process

## ➤ Identification of Actual MPPs

- ✓ Linearized limit states

$$G_p^L(\mathbf{U}) = (\mathbf{U} - \mathbf{MPP}_p) \cdot \mathbf{MPP}_p = 0$$

or

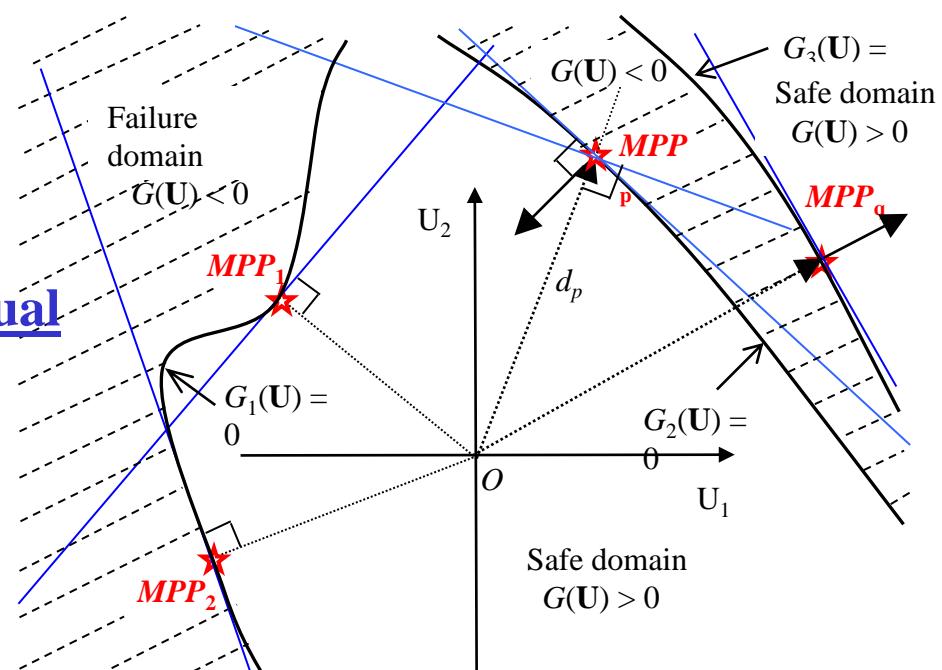
$$G_p^L(\mathbf{U}) = (\mathbf{U} - \mathbf{MPP}_p) \cdot \nabla G_p = 0$$

- ✓ Collinearity criterion for actual MPP

$$\cos \angle(\mathbf{MPP}_p, \nabla G_p) = \frac{\mathbf{MPP}_p}{\|\mathbf{MPP}_p\|} \cdot \frac{\nabla G_p}{\|\nabla G_p\|} = \pm 1$$

- ✓ Practical criterion

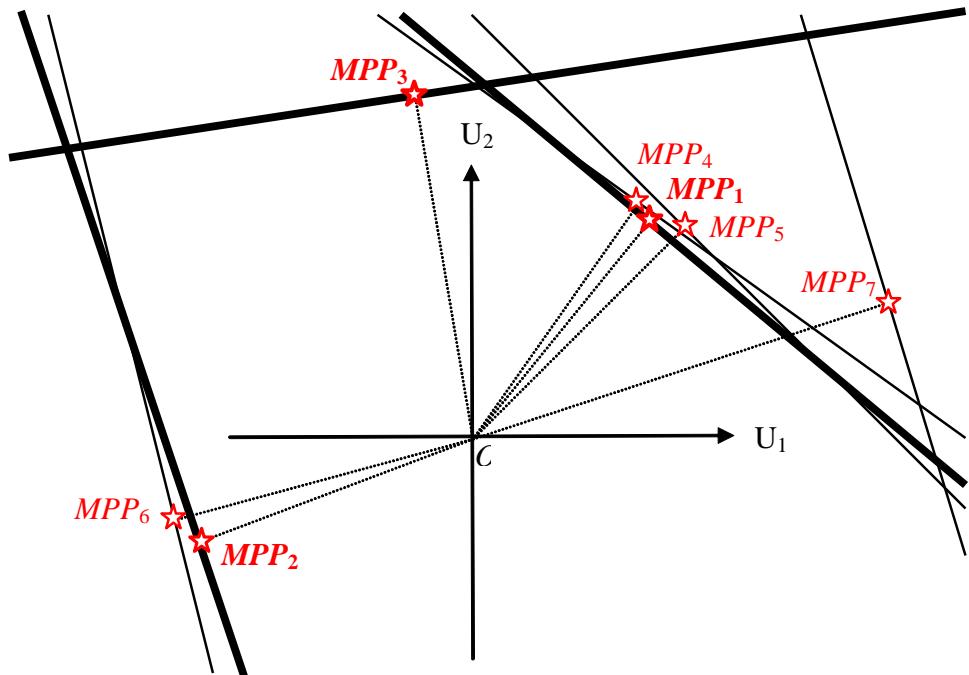
$$\left| \frac{\mathbf{MPP}_p}{\|\mathbf{MPP}_p\|} \cdot \frac{\nabla G_p}{\|\nabla G_p\|} \right| \geq 1 - \varepsilon_{\text{MPP}} \quad 0 < \varepsilon_{\text{MPP}} < 1$$



# Time-dependent Reliability Analysis of a Random Process

- **Identification of Independent and Significant MPPs**
- Two MPPs are independent if the correlation coefficient is very close to +1
- Reliability index identifies significant MPPs

$$\rho_{pq}^L = \cos \angle(\mathbf{MPP}_p, \mathbf{MPP}_q) = \frac{\mathbf{MPP}_p \cdot \mathbf{MPP}_q}{\|\mathbf{MPP}_p\| \cdot \|\mathbf{MPP}_q\|}$$





# Time-dependent Reliability Analysis of a Random Process



## ➤ Estimation of Probability of Failure

- ✓ Convex safe domain formed by linearized limit states

$$\begin{aligned} M_p &: \\ G_p^L(\mathbf{U}) &= \mathbf{U} \cdot \mathbf{MPP}_p - \mathbf{MPP}_p \cdot \mathbf{MPP}_p \\ &\leq 0 \quad \text{for } p = 1, 2, \dots, M \end{aligned} \quad \beta_p^L = \|\mathbf{MPP}_p\|_2$$

- ✓ Second order (bi-modal) bounds

$$p_{f_1} + \sum_{p=2}^M \max \left( p_p - \sum_{q=1}^{p-1} P(M_p \cap M_q), 0 \right) \leq p_f \leq \sum_{p=1}^M p_{f_i} - \sum_{p=2}^M \max_{q < p} P(M_p \cap M_q)$$

- ✓ MCS on the linearized convex safe domain

$$\Omega_f^L = \bigcup_p^M M_p = \bigcup_p^M \left( \mathbf{U} \cdot \mathbf{MPP}_p - \mathbf{MPP}_p \cdot \mathbf{MPP}_p \leq 0 \right)$$

# A Niching GA Method for Identifying Multiple MPPs

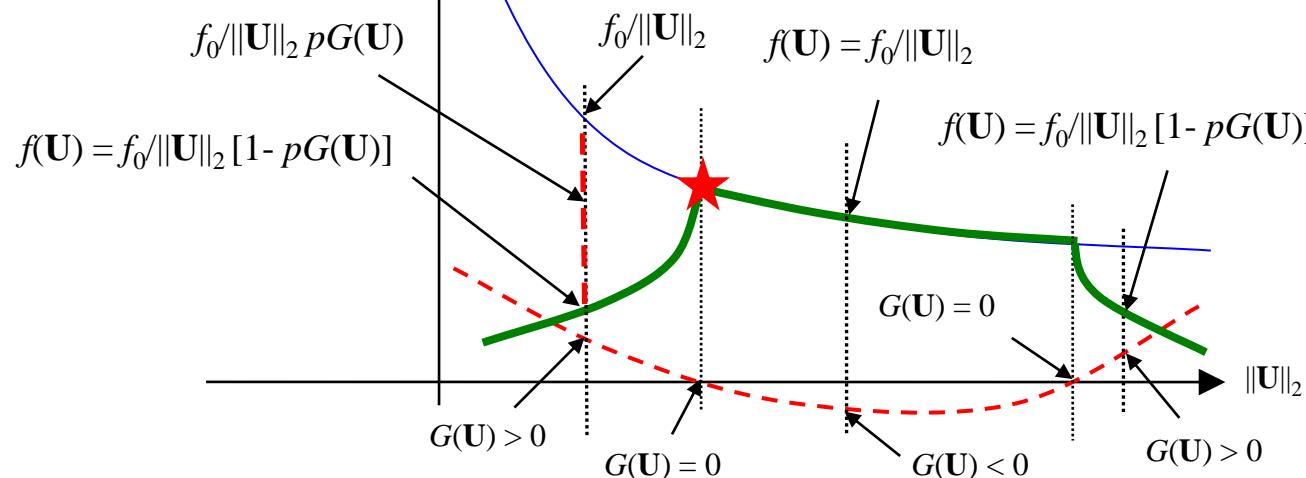
- **Greedy Fitness Sharing**
  - ✓ **Fitness sharing is a popular niching technique.**
    - **Decreases chance of mating in densely populated niches**
    - **Increases chance of mating in sparse niches.**

# A Niching GA Method for Identifying Multiple MPPs

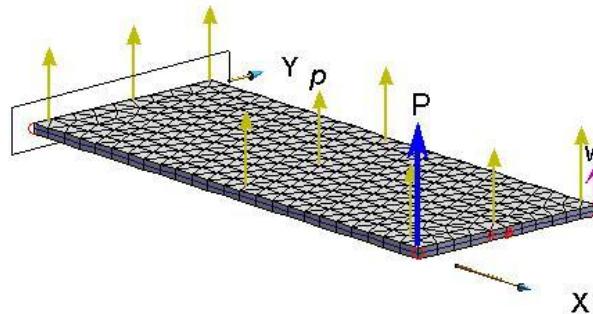
- ✓ Fitness function for identification of MPPs using RIA

$$\left. \begin{array}{l} \beta_j = \min_{\mathbf{U}} \|\mathbf{U}\|_2 \\ \text{s.t. } g(\mathbf{U}) = 0 \end{array} \right\} \Rightarrow \boxed{\max f(\mathbf{U}) = \frac{f_0}{\|\mathbf{U}\|_2} \{1 - p \max[G(\mathbf{U}), 0]\}}$$

Penalty Function Approach



# Numerical Example



## •Model Description

- 3% critical modal damping
- Carried out for 0.1 seconds.

$$P(t) = 25 \cos(300\pi u(t - 0.004)) \text{ lbf}$$

$$p(t) = \cos(500\pi t) \text{ psi}$$

$$w(t) < \underbrace{0.3 \text{ in}}_{|w|_{\max}}$$

# Numerical Example

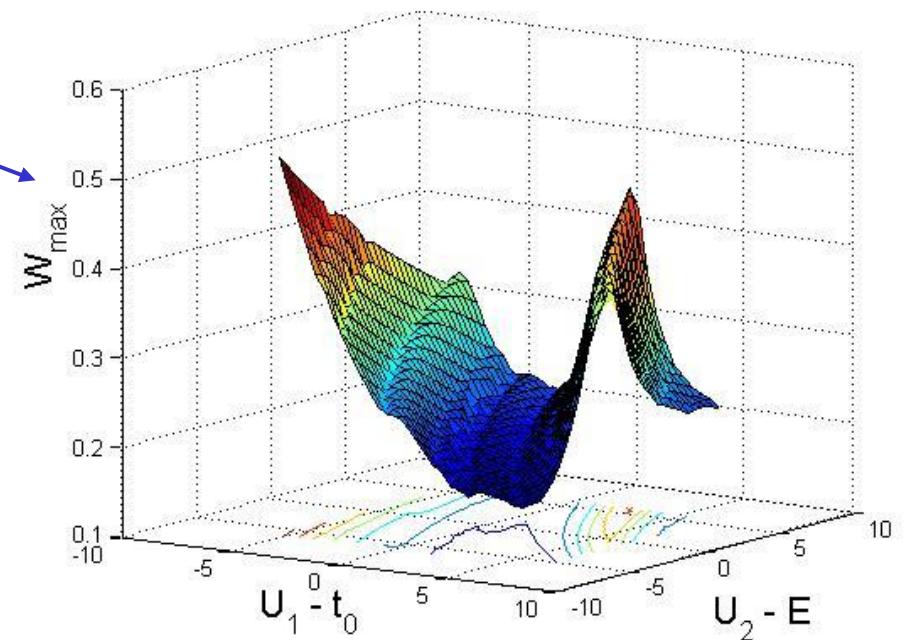
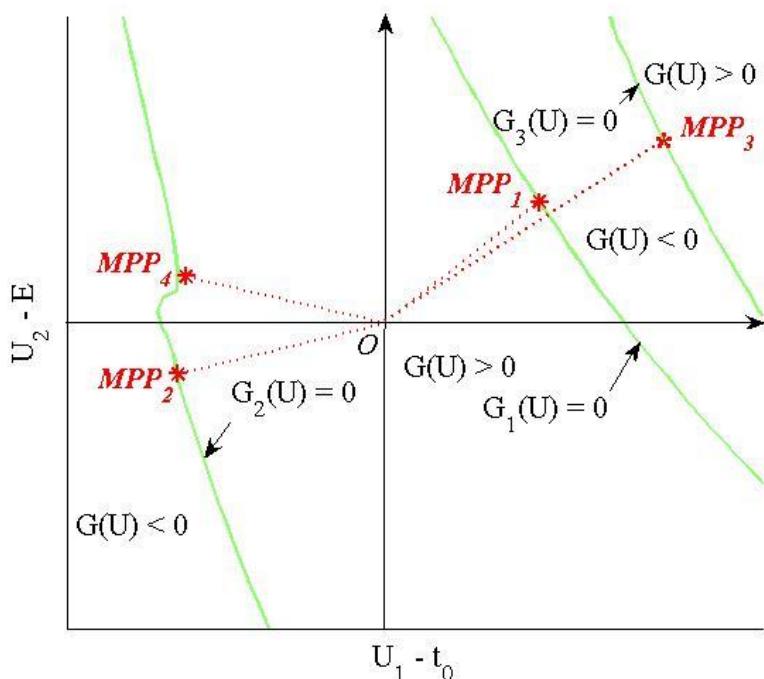
## Plate properties

	Mean $\mu_X$	$Cov = \frac{\sigma_X}{\mu_X}$	Std. Variation $\sigma_X$
Length (a)	2in	0	0
Height (b)	2in	0	0
<b>Thickness</b>	<b>0.0877in</b>	<b>0.0513</b>	<b>0.0045in</b>
Weight Density	0.282 lbs/in <sup>3</sup>	0	0
Mass/Weight Factor	$2.59 \times 10^{-3}$ sec <sup>2</sup> /in	0	0
<b>Young's Modulus</b>	<b><math>30.0 \times 10^6</math> lbs/in<sup>2</sup></b>	<b>0.05</b>	<b><math>15 \times 10^5</math> lbs/in<sup>2</sup></b>
Poisson's Ratio	0.3	0	0

# Numerical Example

Multimodal maximum displacement response

$$S^{\max} = w_{\max}$$



Limit State :

$$G(\mathbf{U}) = w_{\max} - 0.3 = 0$$

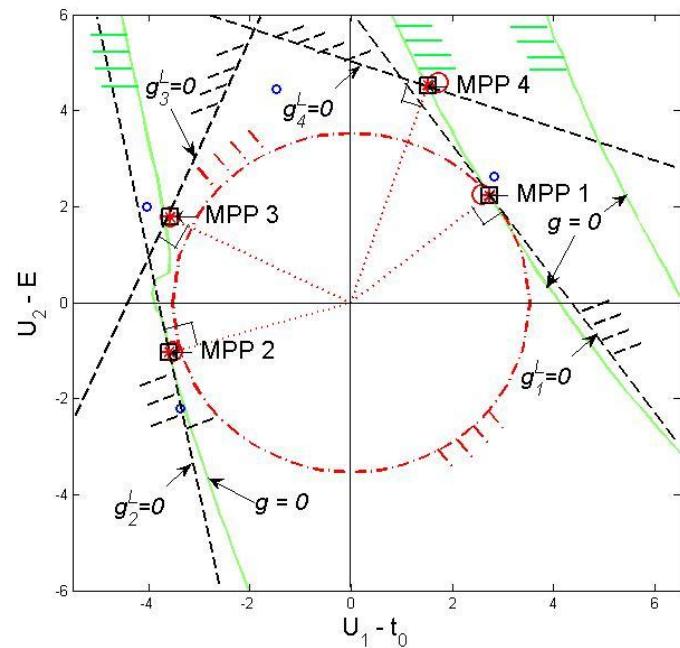
# Numerical Example

- Identification of **independent** and **significant** MPPs.
  - Form a linear approximation of each limit state at each MPP.

$$\rho^L = \left[ \rho_{pq}^L \right]$$

$$= \begin{bmatrix} 1 & -0.9213 & -0.4146 & 0.8444 \\ -0.9213 & 1 & 0.7359 & -0.5696 \\ -0.4146 & 0.7359 & 1 & 0.1373 \\ 0.8444 & -0.5696 & 0.1373 & 1 \end{bmatrix}$$

**Independent MPPs:**  $\rho_{ij} < +0.9$



# Numerical Example

- Estimation of probability of failure using the Ditlevson's second-order bounds:

$$p_f^L = p_f^U = 3.3298 \times 10^{-4}$$

MC simulation with 1,000,000 samples using linearized safe domain yields:

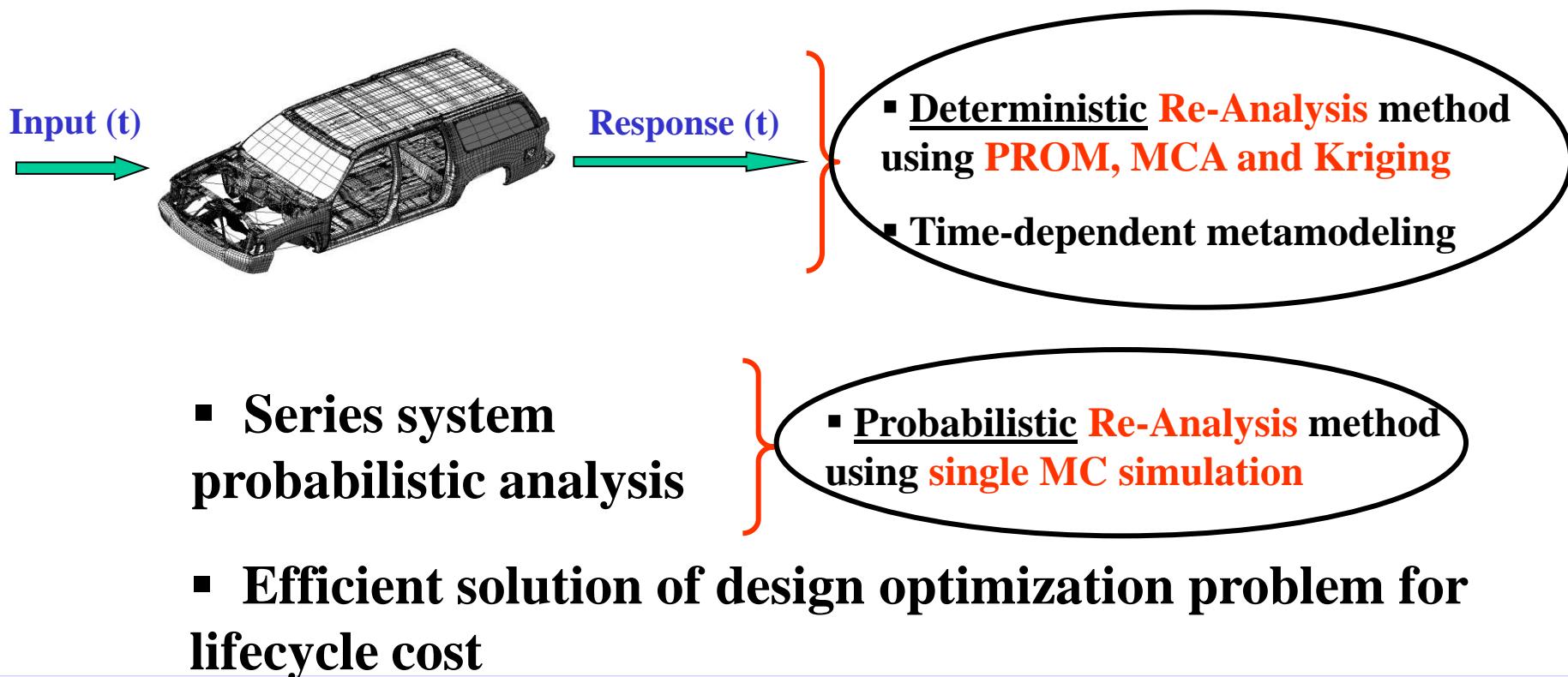
$$P_{f \text{ MCS}}^L = 3.51 \times 10^{-4}$$

If MPP4 is removed:  $p_f = 3.3287 \times 10^{-4}$  

 MPP4 is **insignificant**

- Calculation of **cumulative prob. of failure**

- **Series system approach for  $[0, t_f]$**
- **Reliability estimation at time  $t_L$  ( $0 < t_L < t_f$ ) ; multiple MPP case**





# Q & A

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